# 2.5 V/3.3 V Differential 2:1 MUX to 4 LVDS Clock Fanout Buffer Outputs with Clock Enable and Clock Select

#### Description

The NB3L8543S is a high performance, low skew 1-to-4 LVDS Clock Fanout Buffer.

The NB3L8543S features a multiplexed input which can be driven by either a differential or single–ended input to allow for the distribution of a lower speed clock along with the high speed system clock.

The CLK\_SEL pin will select the differential CLK and  $\overline{\text{CLK}}$  inputs when LOW (or left open and pulled LOW by the internal pull-down resistor). When CLK\_SEL is HIGH, the differential PCLK and  $\overline{\text{PCLK}}$  inputs are selected.

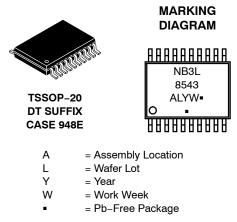
The common clock enable pin, CLK\_EN, is synchronous so that the outputs will only be enabled/disabled when they are already in the LOW state. This avoids any chance of generating a runt clock pulse on the outputs during asynchronous assertion/deassertion of the clock enable pin. The internal flip flop is clocked on the falling edge of the input clock; therefore, all associated specification limits are referenced to the negative edge of the clock input.

### Features

- Four Differential LVDS Output Pairs
- Two Selectable Differential Clock Inputs
- CLK/CLK Can Accept LVPECL, LVDS, HCSL, SSTL and HSTL
- PCLK/PCLK Can Accept LVPECL, LVDS, CML and SSTL
- Maximum Output Frequency: 650 MHz
- Additive Phase Jitter, RMS: 50 fs (typical)
- Output Skew: 40 ps (maximum)
- Part-to-part Skew: 200 ps (maximum)
- Propagation Delay: 1.9 ns (maximum)
- Operating Range:  $V_{DD} = 2.5 \text{ V} \pm 5\%$  or  $3.3 \text{ V} \pm 10\%$
- -40°C to +85°C Ambient Operating Temperature Range
- TSSOP-20 Package
- These are Pb-Free Devices



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(Note: Microdot may be in either location)

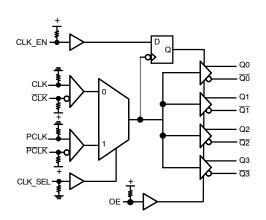


Figure 1. Simplified Logic Diagram

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 10 of this data sheet.

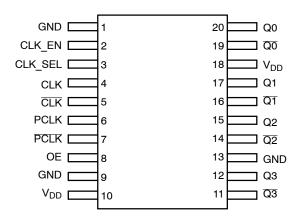


Figure 2. Pinout Diagram (Top View)

### Table 1. PIN DESCRIPTION

Number	Name	I/O	Open Default	Description
1, 9, 13	GND	Power		Negative (Ground) Power Supply pins must be externally connected to power supply to guarantee proper operation.
2	CLK_EN	NC	Pullup	Synchronized Clock Enable when HIGH. When LOW, outputs are disabled (Qx HIGH, $\overline{Qx}$ LOW). See Figure 3.
3	CLK_SEL	NC	Pulldown	Clock Input Select (HIGH selects PCLK/PCLK, LOW selects CLK/ CLK input
4	CLK	Input	Pulldown	True Standard Clock Input. Float open when unused.
5	CLK	Input	Pullup	Invert Standard Clock Inputs. Float open when unused.
6	PCLK	Input	Pulldown	True Peripheral Clock Input. Float open when unused.
7	PCLK	Input	Pullup	Invert Peripheral Clock Inputs. Float open when unused.
8	OE	NC	Pullup	Output Enable Control. When HIGH, the outputs are active and en- abled. When LOW, the outputs are high impedance disabled.
10 ,18	VDD	Power		Positive Power Supply pin must be externally connected to power supply to guarantee proper operation.
11, 14, 16, 19	Q[3:0]	Output		Invert LVDS Outputs
12, 15, 17, 20	Q[3:0]	Output		True LVDS Outputs

### Table 2. FUNCTIONS

	Inputs			Inputs Outputs					
OE	CLK_EN	CLK_SEL	Input Function	Output Function	Qx	Qx			
0	Х	Х			HI–Z	HI–Z			
1	0	0	CLK input selected	Disabled	LOW	HIGH			
1	0	1	PCLK Input Selected	Disabled	LOW	HIGH			
1	1	0	CLK input selected	Enabled	CLK	Invert of CLK			
1	1	1	PCLK Input Selected	Enabled	PCLK	Invert of PCLK			

1. After CLK\_EN switches, the clock outputs are disabled or enabled following a rising and falling input clock edge as show in Figure 3.

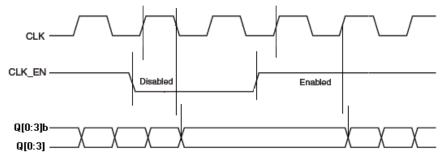


Figure 3. CLK\_EN TIMING DIAGRAM

#### Table 3. ATTRIBUTES (Note 2)

Characteristic	Value		
Internal Input Pullup Resistor	50 kΩ		
Internal Input Pulldown Resistor	50 kΩ		
ESD Protection	Human Body Model Machine Model	> 2 kV > 200 V	
Moisture Sensitivity, Indefinite Time O	Moisture Sensitivity, Indefinite Time Out of Drypack (Note 2)		
Flammability Rating Oxygen Index	UL 94 V–0 @ 0.125 in 28 to 34		
Transistor Count	430		
Meets or exceeds JEDEC Spec EIA/J	ESD78 IC Latchup Test		

2. For additional information, see Application Note AND8003/D.

#### Table 4. MAXIMUM RATINGS (Note 3)

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
V <sub>DD</sub>	Supply Voltage			4.6	V
V <sub>in</sub>	Input Voltage			$-0.5\leqV_{I}\leqV_{DD}+0.5$	V
C <sub>in</sub>	Input Capacitance			4	pF
Ι <sub>D</sub>	Output Current	Continuous Surge		10 15	mA
T <sub>A</sub>	Operating Temperature Range, Industrial			$-40 \text{ to } \le +85$	°C
T <sub>stg</sub>	Storage Temperature Range			-65 to +150	°C
$\theta_{JA}$	Thermal Resistance (Junction-to-Ambient)	0 lfpm 500 lfpm	TSSOP-20	140 50	°C/W °C/W
$\theta_{JC}$	Thermal Resistance (Junction-to-Case)	(Note 4)	TSSOP-20	23 to 41	°C/W
T <sub>sol</sub>	Wave Solder			265	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and not valid simultaneously.

If stress limits are exceeded device functional operation is not implied, damage may occur and reliability may be affected.

4. JEDEC standard multilayer board - 2S2P (2 signal, 2 power).

Symbol	Characterist	c	Min	Тур	Max	Unit
POWER SUPP	LY					
V <sub>DD</sub>	Power Supply Voltage	V <sub>DD</sub> = 3.3 V V <sub>DD</sub> = 2.5 V	2.97 2.375	3.3 2.5	3.63 2.625	V
I <sub>DD</sub>	Power Supply Current				50	mA

#### LVCMOS/LVTTL INPUTS (CLK\_EN, CLK\_SEL, OE)

V <sub>IH</sub>	Input HIGH Voltage	V <sub>DD</sub> = 3.3 V V <sub>DD</sub> = 2.5 V	2 1.7	V <sub>DD</sub> + 0.3	V
V <sub>IL</sub>	Input LOW Voltage	V <sub>DD</sub> = 3.3 V V <sub>DD</sub> = 2.5 V		0.8 0.7	V
Ι <sub>ΙΗ</sub>	Input High Current (V <sub>DD</sub> = V <sub>IN</sub> = 3.63 V)	CLK_EN, OE CLK_SEL		5 150	μA
IIL	Input LOW Current (V <sub>DD</sub> = 3.63 V, V <sub>IN</sub> = 0 V)	CLK_EN, OE CLK_SEL	-150 -5		μΑ

DIFFERENTIAL INPUTS (see Figures 5 and 6) (Note 8)

V <sub>IHD</sub>	Differential Input HIGH Voltage	CLK PCLK	0.5 1.5	V <sub>DD</sub> -0.85 V <sub>DD</sub>	V
V <sub>ILD</sub>	Differential Input LOW Voltage	CLK PCLK	0 0.5	V <sub>IHD</sub> -0.15 V <sub>IHD</sub>	V
V <sub>ID</sub>	Differential Input Voltage (V <sub>IHD</sub> - V <sub>ILD</sub> )	CLK PCLK	0.15 0.30	1.3 1.0	V
VIHCMR	Common Mode Input Voltage; (Note 9)	CLK PCLK	0.5 1.5	V <sub>DD</sub> -0.85 V <sub>DD</sub>	V
Ι <sub>ΙΗ</sub>	Input HIGH Current V <sub>DD</sub>	= V <sub>IN</sub> = 3.63 V <u>CLK</u> , <u>PCLK</u> CLK, <u>PCLK</u>		150 5	μΑ
Ι <sub>ΙL</sub>	Input LOW Current V <sub>DD</sub> = 3.6	63 V, V <sub>IN</sub> = 0 V <u>CLK, PCLK</u> CLK, PCLK	-5 -150		μΑ

### LVDS OUTPUTS

V <sub>OD</sub>	Differential Output Voltage	200	300	360	mV
$\Delta V_{OD}$	VOD Magnitude Change		0	40	mV
V <sub>OS</sub>	Differential Output Voltage Offset Voltage	1.125	1.25	1.375	V
$\Delta V_{OS}$	VOS Magnitude Change		5	25	mV
I <sub>OZ</sub>	Output High Impedance Leakage Current	-10		+10	μΑ
I <sub>OS</sub>	Output Short Circuit Current		-5		mA
V <sub>OH</sub>	Output HIGH Voltage		1.34	1.6	V
V <sub>OL</sub>	Output LOW Voltage	0.9	1.06		V

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

5. Outputs terminated 100  $\Omega$  across Qx and  $\overline{Qx}$ , see Figure 4. DC Measurements per Figure 10 reference.

6.  $V_{th}$ ,  $V_{IH}$ ,  $V_{IL}$ , and  $V_{ISE}$  parameters must be complied with simultaneously. 7.  $V_{th}$  is applied to the complementary input when operating in single-ended mode.

8.  $V_{IHD}$ ,  $V_{ILD}$ ,  $V_{ID}$  and  $V_{CMR}$  parameters must be complied with simultaneously.

9. The common mode voltage is defined as  $V_{IH}$ .

Symbol	Characteristic		Min	Тур	Max	Unit
f <sub>MAX</sub>	Maximum Operating Frequency, $V_{OUTPP} \ge 200 \text{ mV}$	V <sub>DD</sub> = 3.3 V V <sub>DD</sub> = 2.5 V	0 0		650 500	MHz
t <sub>PD</sub>	Propagation Delay	Propagation Delay			1.9	ns
t <sub>∫∲n</sub>	Additive Phase Jitter, RMS; fC = 156.25 MHz Integration Range: 12 kHz – 20 MHz			0.05		ps
t <sub>SKEWO-O</sub>	Output-to-Output Skew Within A Device			15	40	ps
t <sub>SKEWD-D</sub>	Device-to-Device Skew, similar path and conditions	Device-to-Device Skew, similar path and conditions			200	ps
tr/tf	Output rise and fall times @ 50 MHz, 20% to 80%	V <sub>DD</sub> = 3.3 V V <sub>DD</sub> = 2.5 V	150 150	250	500 550	ps
ODC	Output Clock Duty Cycle		45	50	55	%

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

10. Outputs terminated 100  $\Omega$  across Qx and  $\overline{Qx}$ , see Figure 4. Measured from differential crosspoints to differential crosspoints, see Figure 11.

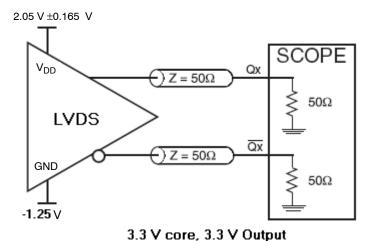
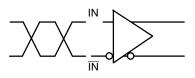
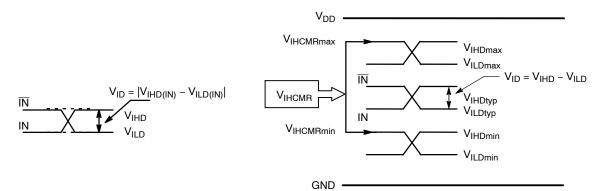


Figure 4. Typical Test Setup and Termination for Evaluation. The V<sub>DD</sub> of 2.05 V  $\pm$ 0.165 V and GND of –1.25 V Split supply allows a direct connection to an oscilloscope 50  $\Omega$  impedance input module.



### Figure 5. Differential Inputs Driven Differentially



### Figure 6. Differential Inputs Driven Differentially



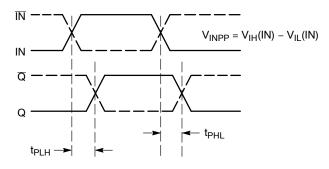


Figure 8. AC Reference Measurement

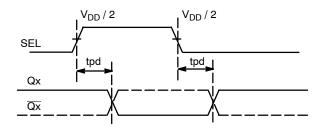
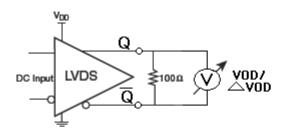
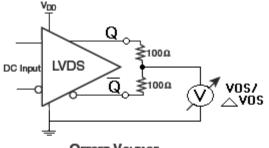


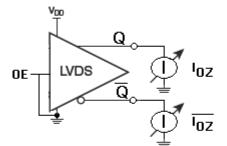
Figure 9. SEL to Qx Timing Diagram



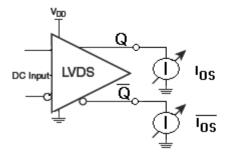


DIFFERENTIAL OUTPUT VOLTAGE



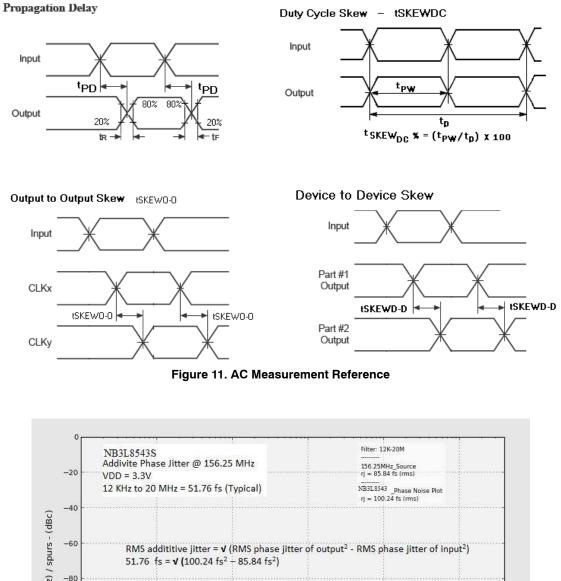


HIGH IMPEDANCE LEAKAGE CURRENT



**OUTPUT SHORT CIRCUIT CURRENT** 

#### Figure 10. DC Measurement Reference



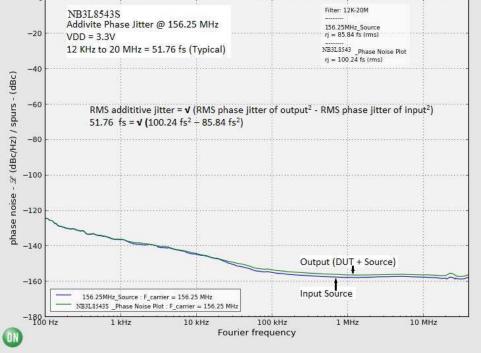


Figure 12. Typical Phase Noise Plot at f<sub>carrier</sub> = 156.25 MHz at an Operating Voltage of 3.3 V, Room Temperature

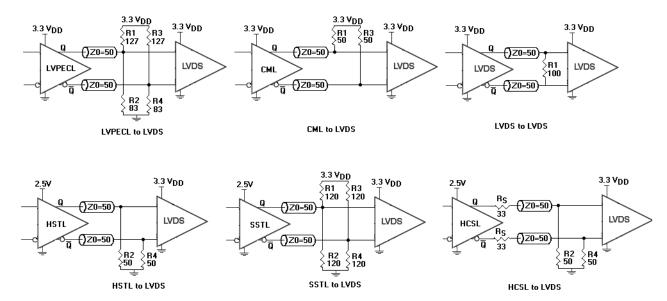


Figure 13. Differential Input Interface From LVPECL, CML, LVDS, HSTL, SSTL, or HCSL

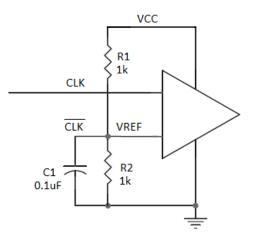


Figure 14. Differential Input Driven Single-ended

### Differential Clock Input to Accept Single-ended Input

Figure 14 shows how the CLK input can be driven by a single–ended Clock signal. C1 is connected to the  $V_{ref}$  node

as a bypass capacitor. Locate these components close the device pins. R1 and R2 must be adjusted to position  $V_{ref}$  to the center of the input swing on CLK.

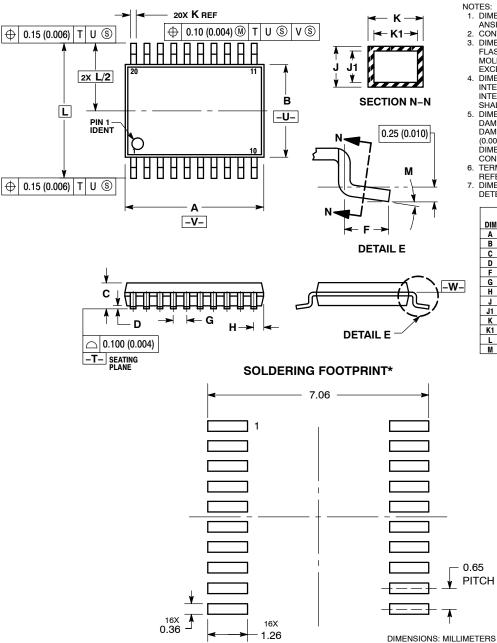
#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NB3L8543SDTG	TSSOP-20 (Pb-Free)	75 Units / Rail
NB3L8543SDTR2G	TSSOP-20 (Pb-Free)	2500 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### PACKAGE DIMENSIONS





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

- NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: MILLIMETER.

- CONTROLLING DIMENSION: MILLIMETER.
  DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
  DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION. SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
  DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION. SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.
- CONDITION. TERMINAL NUMBERS ARE SHOWN FOR
- REFERENCE ONLY.
  DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	6.40	6.60	0.252	0.260
В	4.30	4.50	0.169	0.177
С		1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65 BSC		0.026 BSC	
Н	0.27	0.37	0.011	0.015
L	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
Κ	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252 BSC	
Μ	0°	8°	0°	8°

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